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## Wafer-scale fabrication of two-dimensional PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunctions for efficient and broadband photodetection

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#### **Abstract**

A variety of fabrication methods for van der Waals heterostructures have been demonstrated; however, their wafer-scale deposition remains a challenge. Here we report a simple strategy to create few-layer PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction photodiodes on a 2" SiO<sub>2</sub>/Si substrate that is only limited by the size of work chamber of the equipment, offering throughputs necessary for practical applications. Theoretical simulation results show that the bandgap of PtS<sub>2</sub> is shrunk to half of its original size in the PtS<sub>2</sub>/PtSe<sub>2</sub> heterostructure, while PtSe<sub>2</sub> is almost unchanged, indicating a limited response to the coupling. Both PtSe<sub>2</sub> and PtS<sub>2</sub> layers in the coupled system are still semiconductors. Dynamic photovoltaic switching in the heterojunctions is observed at zero-volt state under laser illuminations of 532 to 2200 nm wavelengths. The PtS<sub>2</sub>/PtSe<sub>2</sub> photodiodes show excellent characteristics in terms of a high photoresponsivity of 361 mAW<sup>-1</sup>, an external quantum efficiency (EQE) of 84%, and a fast response speed. The large-scale production of 2D photodidoes in this work accelerates the possibility of 2D materials for practical applications in the next-generation energy-efficient electronics.

**Keywords**: van der Waals heterostructures, wafer-scale fabrication, dynamic photovoltaic switching, photoresponsivity

#### Introduction

Heterojunctions, firstly invented in 1963 by Herbert Kroemer<sup>1</sup>, have been essential building blocks for electronic and optoelectronic devices in the current semiconductor industry. Uses of such structures have been envisioned in nearly every type of micro devices, including biomedical devices, bipolar transistor, photodiodes, light-emitting diodes, and solar cells. As one of the most important existing optoelectronic devices, the photodiodes obviously play an important role in the applications of video imaging, optical communication, remote control and night vision<sup>2, 3</sup>. However, the diffused and drifted current across the junction can be remarkably influenced by the spatial extent of the depletion region generated in the conventional bulk semiconductor based junctions <sup>4</sup>. One possible way to break the limitation of the spatial extent and improve the performance of the devices is to create a heterojunction fabricated on ultra-thin materials<sup>5, 6</sup>, that contains atomically sharp interfaces. Encouragingly, two-dimensional (2D) transition metal dichalcogenides (TMDs), one important member from the family of atomically thin van der Waals materials, has been widely studied and proved to be of great potential for the applications of future nano-electronics owing to their outstanding electronic, optical, mechanical properties and the strong light-matter interactions<sup>7 8, 9</sup>. Importantly, TMDs have extended bandgap tunability through composition, 10 thickness 11, 12 and possibly even strain control 13 offering infinite flexibility to design 2D junctions in more compelling ways<sup>14, 15, 16, 17, 18, 19</sup>, which has shown great potential applications in photovoltaics, photodiodes and light emitters<sup>11, 15,</sup> <sup>20</sup>, and even could be possible to overcome some of the existing problems in conventional junction devices.<sup>21</sup>

Driven by the diversity and considerable wide coverage properties of TMDs materials, it is really feasible to fabricate artificial 2D van der Waals junctions, <sup>18, 22</sup> using either homogeneous or heterogeneous 2D materials. The formation of 2D homojunction can be formed by chemical/gate-induced electrical doping in the same nanoflake which lacks stability or makes device structures complicated. <sup>23, 24, 25</sup> The fabrication of 2D heterojunctions, however, mainly extends directly to materials

produced by exfoliation from the bulk counterpart using a variety of techniques<sup>18, 26</sup>, but indirectly to those that can be deposited onto targeted substrates with facile control for the practical realization of high-volume manufacturing. Controlled and large-scale integration of more than one type of 2D material into a single structure still remains one of the most challenging tasks.

Recently, the group 10 metal based TMDs have attracted intense interests for the widely tunable band gap, large electrical conductivity and high air stability, which can well make up the drawbacks of graphene (zero band gap), most TMDs semiconductors (relatively large band gap), and black phosphorus (poor air stability). Representative examples of this family are platinum diselenide (PtSe<sub>2</sub>) and platinum disulfide (PtS<sub>2</sub>) that can be synthesized via a single step, i.e. direct selenization (or sulfuration) of the Pt substrate<sup>27, 28</sup>. Layered PtSe<sub>2</sub> has a tunable bandgap ranging from 1.2 eV (monolayer) to semimetal (bulk)<sup>29</sup>, while layered PtS<sub>2</sub> has a bandgap varies from 1.6 eV in monolayer to 0.25 eV in bulk<sup>30</sup>. The large spread of bandgaps from visible to midinfrared is similar to that of layered black phosphorus (BP), revealing potential for infrared electronic application. Compared to other extensively studied TMDs, such as MoS2, WS2, WSe2 etc, field-effect transistors based on PtSe2 layers exhibit higher mobility at room temperature, comparable to that of BP, suggesting that this material is applicable for high-performance electron transport devices<sup>31</sup>. Furthermore, few-layer PtSe2 nanosheets have also been used to make infrared photodetectors with good photoresponsivity and fast response<sup>31,32</sup>. Another case is few-layer PtS<sub>2</sub> phototransistor that shows high photoresponsivity and photoconductive gain due to the existence of trap states<sup>33</sup>. Although the optoelectronic properties of individual 2D group-10 TMDs have been preliminary studied, the comprehensive study of van der Waals like interlayer coupling of two different group-10 TMDs that can dramatically affect the bandstructures and optoelectronic properties of 2D TMDs, and their 2D heterojunction diodes is still lacking. Moreover, existing TMDs/TMDs heterostructures reported to date display a spectral response that is mainly limited to visible wavelengths by the intrinsic band gap of the constituting materials<sup>34</sup>. By combining the advantages of ultrahigh stability and infrared photoresponse, 2D heterojunction diode based on group10 TMDs are promising for low-power and high frequency optoelectronics at infrared wavelengths.

Herein, we report a simple strategy to create few-layer van der Waals PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunctions on the surfaces of planar substrates to enable large-area manufacturing of 2D heterostructure diodes based on group-10 TMDs. Such a 2D heterojunction can simply be formed directly through selenization (or sulfuration) of the Pt substrate by changing the Se source from S on the Pt layer using an ambient pressure conversion process. The coverage, size, and shape of PtSe<sub>2</sub> onto PtS<sub>2</sub> film can be controlled as desired, and their thicknesses were determined by the thicknesses of the pre-deposited Pt film. Methods based on above process are naturally compatible with modern planar technologies, and they offer throughputs necessary for practical applications. Theoretical simulation results show that the bandgap of PtS<sub>2</sub> is shrunk to half of its original size in the PtS2/PtSe2 heterostructure, while PtSe2 is almost unchanged, indicating a limited response to the coupling. Both PtSe<sub>2</sub> and PtS<sub>2</sub> layers in the coupled system are still semiconductors. Dynamic photovoltaic switching in the heterojunctions is observed at zero-volt state under laser illuminations of 532 to 2200 nm wavelengths. Upon optical illumination, the self-driven PtS2/PtSe2 photodiodes show excellent characteristics in terms of a high photoresponsivity of 361 mAW<sup>-1</sup> and an external quantum efficiency of 84% at 532 nm. These diodes show promise for broad-band photodetection and solar energy harvesting.

#### **Results and Discussion**

The vertical heterojunction arrays (see Figure 1a and 1b for a microscope image) were obtained on an oxide silicon wafer with 300 nm thick silicon dioxide. They consist of few-layer PtS<sub>2</sub> and PtSe<sub>2</sub> films that were synthesized via direct selenization or sulfuration of the Pt substrate by changing the Se source from S on the Pt layer using an ambient pressure conversion process (see Methods for more details). Our fabrication process enables manufacturability of wafer-scale production of 2D heterojunctions for optoelectronic applications, and the maximum sample size obtained in our experiment is up to 2" in diameter limited by the work chamber of the equipment. From the high-

resolution optical microscopy images (Figure 1c), we can observe that the PtS2 and PtSe2 sheets are well-defined with very uniform contrast, irrespective of a single PtS2 or PtSe2 sheet or their overlap region, which is attributed to the delicate control of growth process, proper thermal budget and homogeneous thickness of PtS2 and PtSe2 sheets. The size of PtS2 sheets and PtSe2 sheets were designed to be  $100 \times 120 \,\mu\text{m}^2$  and  $100 \times 100 \,\mu\text{m}^2$ , respectively. The reason that the overlap part did not mix together to form a lateral hybrid film of PtS2-PtSe2 is due to the two-step growth process we have employed. Atomic force microscopy (AFM) was used to probe the detailed surface morphology and the thicknesses of PtS2, PtSe2 sheets, and their vertical heterojunctions (Figure 1c). The AFM height profile indicates that the thickness of PtS2/PtSe2 heterojunction is  $\sim 5.1 \, \text{nm}$ . We have also measured the pure PtS2 and PtSe2 regions, respectively. The thicknesses of PtS2 and PtSe2 are measured to be  $\sim 2.4 \, \text{and} \sim 2.7 \, \text{nm}$ , corresponding to five layers of PtS2 and five layers of PtSe2, respectively.

Raman spectroscopy was utilized to identify and characterize the obtained PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction films. Figure 1d shows the polarization-dependent Raman spectra of PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction excited by the 633 nm laser. Both the feature peaks of PtS2 and PtSe2 are observed in the spectra. The as-grown PtSe2 films show two feature peaks at ~176 cm<sup>-1</sup> and ~210 cm<sup>-1</sup> which correspond to the  $E_g$  and  $A_{Ig}$  Raman active modes of PtSe<sub>2</sub>, respectively. The  $E_g$  mode is an in-plane vibrational mode of Se atoms moving away from each other within the layer, while the  $A_{1g}$  mode is an out-ofplane vibration of Se atoms in opposing directions. There is also a small peak located at ~230 cm<sup>-1</sup> which can be attributed to a longitudinal oscillation (LO) mode, similar to those observed in HfS2, ZrS2 and CdI2.35, 36 For PtS2, three main peaks at about 307, 335, and 340 cm<sup>-1</sup> can be assigned to  $E_g^1$ ,  $A_{1g}^1$ , and  $A_{1g}^2$  phonon modes, respectively. On the basis of previously theoretical prediction and experimental observations<sup>37</sup>, we know that these two out-of-plane modes,  $A^1_{1g}$  and  $A^2_{1g}$  are observable in the polarization-dependent Raman spectra of PtS<sub>2</sub>, while their intensities are polarizationdependent. This phenomenon can also be found in our experiment as shown in Figure 1d, the difference is that the intensity disparity between these two modes are not as obvious as the previously reported results because the samples in our experiments are formed with fine grains, as verified by X-ray diffraction (XRD), transmission electron microscopy (TEM) and Scanning TEM (STEM), as elucidated in the following part. Furthermore, Raman mapping images (inset of Figure 1d) indicate that the overlap part of the PtSe<sub>2</sub> and PtSe<sub>2</sub> sheet are well-separated, where the PtSe<sub>2</sub> sheet stacks on the top of the PtSe<sub>2</sub> sheet. The crystal structures of PtSe<sub>2</sub> and PtSe<sub>2</sub> films were further explored by XRD, as shown in Figure S1. The layered PtSe<sub>2</sub> and PtSe<sub>2</sub> film can be viewed as cleaved from the (0001) surface of the bulk PtSe<sub>2</sub> and PtSe<sub>2</sub>, where one Pt atom layer is sandwiched between two S or Se layers (PtSe<sub>2</sub>: JCPDS PDF No. 01-070-1140, PtSe<sub>2</sub>: JCPDS PDF No. 01-088-2280). The main XRD diffraction peaks of PtSe<sub>2</sub> films are observed at about 17.6°, 34.6°, and 54.6°, which can be indexed to the (001), (002) and (003) crystal planes of PtSe<sub>2</sub>, respectively, suggesting that PtSe<sub>2</sub> film grows along c-direction with (001) as bottom plane, which agrees very well with the previous reports.<sup>38, 39</sup> Similar results were found for the PtSe<sub>2</sub> film. It is noteworthy that the diffraction peaks of Pt (111) disappeared after selenization or sulfuration which indicates a complete conversion of Pt into PtSe<sub>2</sub> and PtSe<sub>2</sub> crystals.

The X-ray photoelectron spectroscopy (XPS) was also used to determinate the elemental binding energies of PtS<sub>2</sub>, PtSe<sub>2</sub> sheets, and their vertical heterojunctions, as shown in Figure 1e. XPS spectra of the Pt 4f, Se 3d and S 2P regions were acquired on the heterojunction sample. The measurement results for the binding energies demonstrate the formation of PtS<sub>2</sub> and PtSe<sub>2</sub>. The peak positions at 54.39 and 55.19 eV corresponds to the binding energy of Se<sup>2-</sup>. Besides, two other peaks located at 73.9 and 77.3 eV of Pt 4f spectrum can be assigned to the Pt 4f<sub>2/7</sub> and Pt 4f<sub>2/5</sub>. Two peaks at 162.3 and 163.6 eV of S 2p spectrum displayed are ascribed to binding energy of Pt-S bonds between adjacent Pt atoms and S-S bonds, respectively, similar to the previous results.<sup>38, 40</sup> To check the purity of the materials, Figure 1f displays the corresponding Pt, S and Se mapping images obtained by energy dispersive X-ray spectroscopy, which confirms that all the elements are homogeneously distributed throughout the entire structure.

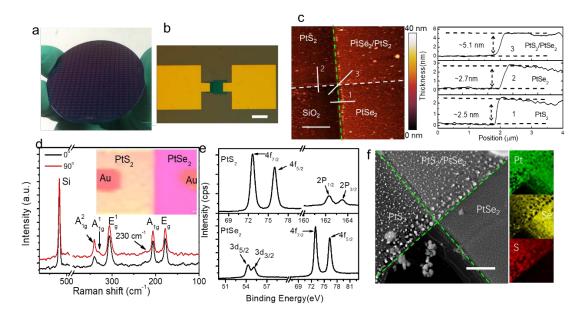


Figure 1

To further assess the microstructure, crystallinity, and elemental composition of the as-grown PtS<sub>2</sub>/PtSe<sub>2</sub> vertical heterojunctions, the samples were transferred onto copper grid using the poly(methyl methacrylate) (PMMA) assisted transfer method<sup>41</sup> and investigated by TEM and STEM, as shown in Figure S2. The low-magnification TEM image (Figure S2b and Figure S2e) indicates that the PtSe<sub>2</sub> and PtS<sub>2</sub> nanosheets have good uniformity and continuity across the whole platelet. The inset in Fig. S2b shows the selected area electron diffraction (SAED) pattern of PtSe<sub>2</sub> nanosheet, which confirms the obtained sample is polycrystalline and the four distinguished red dashed circles are assigned to (001), (101), (111) and (201) planes with lattice spacings of 5.15, 2.77, 1.55 and 1.75 Å, respectively. The inset in Fig. S2e shows the SAED pattern of PtS<sub>2</sub> nanosheet, which confirms the obtained sample is polycrystalline and the four distinguished red dashed circles are assigned to (101), (102), (111) and (202) planes with lattice spacings of 2.61, 1.93, 1.65 and 1.29 Å, respectively. The high-resolution TEM (HRTEM) image of the PtSe<sub>2</sub> nanosheet in Figure S2c reveal clear lattice fringes with a lattice spacing of 0.287 nm corresponding to (101) facets of PtSe<sub>2</sub> nanosheet, while for the PtS<sub>2</sub> nanosheet, the lattice space is 0.261 nm as shown in Figure S2f.

To gain basic understanding of the electronic properties and band structure information of the PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction, theoretical simulations were conducted using the Vienna ab initio simulation package. Details of the simulation process is

shown in Methods. The atomic geometries for layered PtSe<sub>2</sub>, PtS<sub>2</sub> and coupled structure are shown in Figure 2 (a-c). The 1T phase is selected since it is the most stable structure in the simulation. The thickness of 5L-PtSe<sub>2</sub> and 5L-PtS<sub>2</sub> are 27.6 Å and 24.4 Å, comparable to the experimental value of 2.7 nm for PtSe2 and 2.4 nm for PtS2 respectively. Distances between adjacent Pt atoms in PtSe<sub>2</sub> and PtS<sub>2</sub> are 3.74 Å and 3.58 Å, respectively. When modeling coupled structure of PtSe<sub>2</sub> and PtS<sub>2</sub>, the lateral lattice parameter of PtS<sub>2</sub> is slightly expanded in order to fix in the unit cell. Both 5L PtSe<sub>2</sub> and PtS<sub>2</sub> in 1T phase are observed to be semiconductors in experiments <sup>31, 33, 38, 40</sup>. Figure 2 d-f show the simulated band structures. 5L-PtSe<sub>2</sub> has an indirect band gap of 0.21 eV. The conductance band minimum (CBM) is settled between Gamma and M point, while the valance band maximum (VBM) is slightly offset from Gamma point. 5L-PtS2 is also a semiconductor with indirect band gap of 0.89 eV. For the band structure of coupled system shown in panel f, the calculated band structure is only 0.03 eV, which seems to indicate a much more metallic feature, corresponding to a wide spread wavelength range. The plotted bands are a mixture of states from both PtS2 and PtSe2, which cannot represent the electronic properties of PtS2 or PtSe2 layers separately. It also needs to mention that adjusting the lattice parameter of PtS2 slightly decreases its bandgap by around 0.3 eV according to simulation. In order to give a better estimation of the bandgap for each type of material, the projected density of states (PDOS) for Pt and Se/S atoms are also shown adjacent to band structures. By comparing the PDOS before and after the coupling, it can be found that the bandgap of PtS<sub>2</sub> is shrunk to half of its original size. Part of the shrink is caused by changing the lattice parameter. The PDOS of PtSe<sub>2</sub> is almost unchanged, indicating a limited response to the coupling. Both PtSe<sub>2</sub> and PtS<sub>2</sub> layers in the coupled system are still semiconductors since clear bandgaps are present in the PDOS plot, therefore it is naturally interesting to investigate the photovoltaic behavior of the heterostructure.

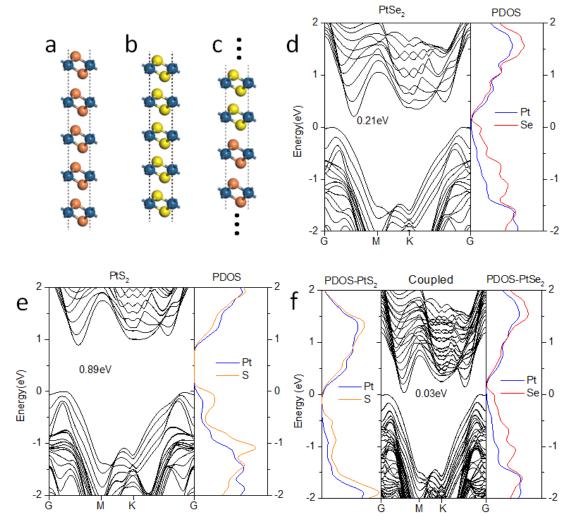


Figure 2. Atomic geometries. (a-c) and band structures. (d-f) of PtSe<sub>2</sub> and PtS<sub>2</sub>. Blue, orange and yellow spheres in panel. (a-c) represent Pt, Se and S atoms respectively. 5L-PtSe<sub>2</sub> and 5L-PtS<sub>2</sub> are used in the coupled system in panel c. Some layers are not displayed in the figure in order to make the appearance clearer. The width of bandgap is inserted in band structure panels (d-f). Projected density of states (PDOS) for Pt and Se/S atoms are also shown adjacent to band structures.

Figure 3 shows a schematic illustration of the photodiode devices based on the  $PtS_2/PtSe_2$  heterostructure, the corresponding current-voltage (*I-V*) characteristics in dark and under illumination, and the schematic band diagrams. The juction shows the typical diode *I-V* dependence as seen from Figure 3b. At positive bias voltage, the current gradually enhances with the applied voltage ( $V_{SD}$ ) due to the increase of carrier density. The Figure S3 shows the perfect Ohmic contact on  $PtSe_2$  and  $PtS_2$ , or a negligible barrier exists that does not significantly affect the rectifying characteristic.

The few-layered PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction demonstrates low-voltage operation, the photovoltage ( $V_{\rm ph}$ ) and photocurrent ( $I_{\rm ph}$ ) are deduced to be 14.6 mV and 0.32  $\mu$ A under a light power of 300 mW at 1064 nm, respectively.

To determine the band alignment at the PtS<sub>2</sub>/PtSe<sub>2</sub> interface, we performed ultraviolet photoelectron spectroscopy (UPS) measurements to determine the band edge energies (Supporting Information, Figure S4). The results show that PtS<sub>2</sub> exhibits a little higher work function of 4.99 eV than that of PtSe<sub>2</sub> (4.93 eV). The work function offset (75 meV) between PtS2 and PtSe2 should block electron flow from the PtS2 film to the PtSe<sub>2</sub> film after contact. Furthermore, the distance between the Fermi level (E<sub>F</sub>) and valence band edge (Ev) in  $PtS_2$  is larger than that in  $PtSe_2$ . To further evaluate the energy offset at the PtS2/PtSe2 heterojunction interface and identify direction of the photocarriers transportation, kelvin probe force microscopy (KPFM) measurements were performed and the representative KPFM image is shown in Figure S5a of Supporting Information. Figure S5b shows the surface potential taken along the solid lines in Figure S5a. The surface potential of the PtS2 film is lower than that of the PtSe<sub>2</sub> film with a work function difference of approximately 35 meV. The difference of work function with UPS measurements in these two materials is because of the different environment in measurement, i.e. in air for KPFM measurement and in vacuum for UPS measurement. Notably, after contact, the surface potential of PtSe<sub>2</sub>/PtS<sub>2</sub> film is promoted in comparison to pristine PtSe<sub>2</sub> film, suggesting electrons are transferred from PtS<sub>2</sub> to PtSe<sub>2</sub> after contact, in good agreement with the UPS measurement result. Therefore, the photo-induced current generation process in our 2D heterojunction is explained in the schematic band diagrams of Figure 3c,d. The estimation of energy levels are based on our theoretical calculation results along with the KPFM, UPS experimental verification. An energy band diagram of individual PtS2 and PtSe2 systems before heterojunction formation is shown in Figure 3c. After contact, the fermi levels in these two materials are shifted and so as to satisfy the equilibrium condition due to the work function mismatch, as shown in Figure 3d. The electrons diffuse from PtSe<sub>2</sub> to PtS<sub>2</sub> and forms a built-in electric field, which leads to band bending between these two materials so as to facilitate effective transportation of photo-excited carriers.

Figure 3d also illustrates the generation and transfer of photo-excited electron-hole pairs under light illumination. Under photo illumination, electron-hole pairs will be generated and then separated by the built-in electric field, part of the photogenerated electrons diffuse from PtS<sub>2</sub> towards the junction and are swept into PtSe<sub>2</sub>, while holes move towards the PtSe<sub>2</sub>. These photocarriers eventually are collected by the electrodes to give rise to a net current. The built-in electric field at the junction interface ensures that the device can operate at zero external bias voltage.

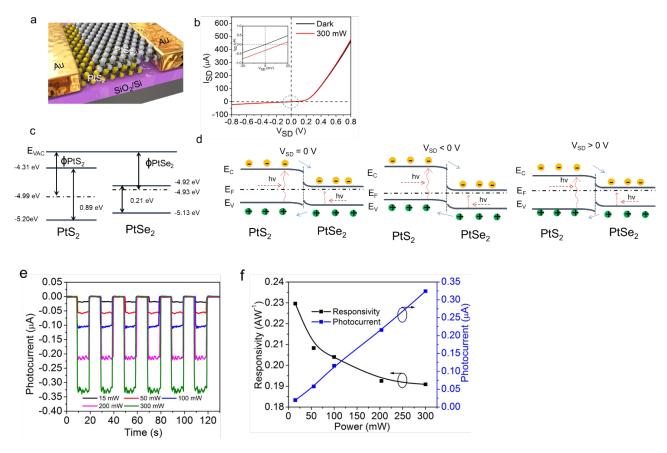


Figure 3

Figure 3e shows the typical photocurrent switching performance of the heterostructure at the infrared wavelength of 1064 nm without external bias voltages  $(V_{SD} = 0 \text{ V}, V_G = 0 \text{ V})$ . Dynamic photovoltaic switching is observed at zero-volt state under different laser powers. This kind of self-powered photodiode can have large numbers of applications like powerless communications, biological and chemical imaging in a wireless healthcare platform, and so on.

Responsivity is an important figure of merit for a photodetector and reflects its sensitivity to the incident light. Figure 3f shows the dependence of photocurrent and

responsivity on incident light power at zero-volt state. The photocurrent increases linearly while promoting the light power, while the responsivity decreases as the increase of incident power, in consistant with the behavious of other TMDs-based photodiode reported before.<sup>42, 43</sup> By contrast, a responsivity ( $R = I_{photo}/P_{incident}$ ,  $I_{photo}$  is the photocurrent and  $P_{incident}$  is the incident power) of 170 mAW<sup>-1</sup> was obtained at low incident power (15 mW), which is comparable to must of reported values for heterojunction photodetectors at infrared wavelength. <sup>43, 44</sup>

With the aim to demonstrate the capability of the broadband ligh detection of our device, a series of photoelectric measurements were performed at different wavelengths. The temperal photoresponse with various wavelengths under the same light power (15 mW) is shown in Figure 4a. The device can be effectively switched ON and OFF while the light source is turned on and off even in the wavelength of 2200 nm (See the powerdependent photoresponse at 2200 nm in Figure S6, Supporting information). The overall profile of the wavelength-dependent photocurrent (Figure 4b) is highly consistent with the absorption spectrum of PtSe<sub>2</sub>, due to the smaller bandgap and wider light absorption ability of PtSe<sub>2</sub>. The wavelength-dependent responsivity (Figure 4c) under the same light power shows a highest value of about 308 mAW<sup>-1</sup> under the visible light illumination (532 nm, 15 mW) and then decreases as the photon energy decreases. The power-dependent photoresponse was also investigated and the results are shown in Figure S7 of Supporting Information. An ultrahigh respnsivity of 361 mAW-1 is revealed, which is the best reported value among the reported values for TMDs-based photodiode. 45, 46 The external quantum efficiency EQE represent the ratio of the number of collected charge carriers to the number of incident photons. It can be calculated by the formula EQE =  $(I_{photo}/P_{incident}) \times \frac{q\lambda}{hc}$ , where  $\lambda$  is 532 nm of the wavelength and obtain EOE ~84%. 45, 47

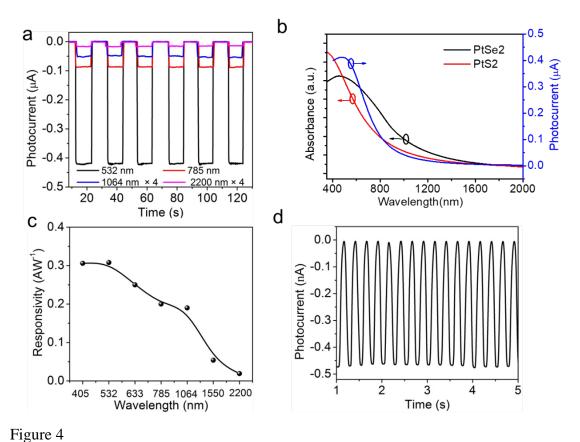


Table 1 PtS2/PtSe2 – Comparison with Other Heterojunction

Materials	Measurement Conditions	Responsivity (mA/W)	EQE	Response time (ms)	Range of response wavelength (nm)	Reference
MoTe <sub>2</sub> /MoS <sub>2</sub>	Vsd = 0 V 405 nm 800 nm	320 38	88% 6%	25 ms	400-800	Adv. Mater. 2016, 28, 3216
MoS <sub>2</sub> /WSe <sub>2</sub>	Vsd = -1 V 590 nm	11	1.5%	*	*	Nano Lett. 2014, 14, 4785–4791
MoS <sub>2</sub> /WSe <sub>2</sub>	Vsd = 0 V 532 nm	120	34%	*	500-800	Nat. Nanotechnol. 2014, 9, 676
BP/MoS <sub>2</sub>	Vsd = -2 V 633 nm	518	0.3%	*	*	ACS nano 2014, 8 (8) :8292
PtS <sub>2</sub> /PtSe <sub>2</sub>	Vsd = 0 V 532 nm 1064 nm	361 170	84% 20%	48 ms	405-2200	This work

We further investigate the response speed of PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction photodetector by shining the device with pulsed light that is modulated by an optical chopper as shown in Figure 4d. The response of the photodiodes is very fast with the rise and decay times of 78 ms and 48 ms (Supporting Information, Figure S8a). The light response of the PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunction remains highly stable after 60 days under

the same illumination conditions, showing the excellent stability of the device in air at room temperatrue (Supporting Information, Figure S8b), which is very important for the practical implementation of this device in long-term operation. The performance of our PtS2/PtSe2 heterojunction devices is compared to other TMDs-based heterojunction photodiodes, as summarized in Table 1. The overall performance of our device is superior to existing MX2/MX2 (M = Mo, W; X = S, Se, Te) heterostructures in terms of working spectral range, responsivity, and EQE. We attribute the excellent photoresponse of PtS2/PtSe2 heterostructure to the effective carrier transportation and enhanced light absorption considering the semiconductor-to-semimetal bandgap transition in the coupled system. Note that the response time is comparable to pristine PtS2 photodetector mainly limited by the existence of trap states<sup>33</sup>, which may be further improved by optimizing the material quality and growth process.

#### **CONCLUSION**

In summary, PtS<sub>2</sub>/PtSe<sub>2</sub> heterojunctions were produced by a two-step chemical vapor deposition methods, where the size, density, and geometry of 2D sheets can be adjusted as desired. Due to the built-in electric field at the interface of the heterojunction, it can be used for a self-driven photodetector without applying a source—drain bias. The self-driven PtS<sub>2</sub>/PtSe<sub>2</sub> photodetectors showed excellent characteristics in terms of wide photoresponse range from 405 to 2200 nm, high photoresponsivity of 361 mAW<sup>-1</sup> and EQE of 84%. The approach demonstrated here is also transplantable for making a variety of TMDs heterojunctions and may open up more possibilities toward large-scale optoelectronic applications.

#### **Methods**

**Synthesis of the PtS<sub>2</sub>/ PtSe<sub>2</sub> heterojunctions.** A two-step chemical vapor deposition approach was developed to produce wafer-scale PtS<sub>2</sub>/ PtSe<sub>2</sub> heterojunctions by using a double heating area furnace. In step one, photoresist was first spin-coated on the SiO<sub>2</sub>/Si substrate and exposed to form the array of periodic square holes. Subsequently, 0.8 nm Pt was deposited by electron beam evaporation to the corresponding square holes. Then

the SiO<sub>2</sub>/Si substrate with Pt was placed into the quartz tube at the downstream and heated to 600 °C and sulfur powder was then put at the upstream with 130 °C. Ar (argon) was introduced as the carrier gas (flow rate: 60 sccm). The SiO<sub>2</sub>/Si substrates with Pt was maintained at 600 °C for 2 hours to form PtS<sub>2</sub>. In step two, photoresist was spin-coated on the SiO<sub>2</sub>/Si substrate with PtS<sub>2</sub> array and exposed again to form the periodic rectangle hole array on part of the PtS<sub>2</sub> sheets. After that, 0.8 nm Pt was then deposited by electron beam evaporation to form the periodic rectangle Pt arrays. Following, similar to the process of producing PtS<sub>2</sub> mentioned above, the furnace temperature was kept at 450 °C for 2 hours to prepare PtSe<sub>2</sub>.

**Fabrication of the PtS2/ PtSe2 heterojunctions devices.** The PtS2/ PtSe2 heterojunctions devices fabrication process involves UV lithography to define the source-drain electrodes pattern and 5 nm Ti/80 nm Au evaporation to deposit the source -drain electrodes.

Characterization of PtS<sub>2</sub>/ PtSe<sub>2</sub> heterojunctions. The morphology and structure of the synthesized nanomaterials were characterized by optical microscopy (OM, Olympus DX51), scanning electron microscopy (SEM, (FEI Quanta 200 FEG, acceleration voltage: 5 30 kV)), atomic force microscopy (AFM, Digital Instrument Nanoscope IIIA), transmission electron microscopy (TEM, FEI Tecnai F30, acceleration voltage: 200 kV), and micro-Raman spectroscopy (Horiba, LabRAM HR-800). X-ray photoelectron spectroscopy (XPS) was performed on a KRATOS AXIS Ultra DLD (KRATOS Analytical C.O.). Photoelectric measurements was performed on a probe station (Cascade M150) equipped with a semiconductor property analyzer (Keithley 4200) in ambient conditions. More photoelectrical properties of the devices are described in the Supporting Information.

**Simulations of the energy band of the PtS<sub>2</sub> and PtSe<sub>2</sub>**: Simulations were conducted using the Vienna ab initio simulation package<sup>48</sup>. The wave function was described by a plane-wave basis set with projected augmented wave method<sup>49, 50</sup>. The exchange-correlation functional was simulated with the optB86b exchange function<sup>51</sup> and van der Waals density functional method<sup>52, 53</sup>, which was found to be accurate in reproducing layered structures<sup>54, 55, 56, 57</sup>. Energy cutoff for the plane wave basis was set to 400 eV

in structural relaxations and increased to 500 eV in static calculations. Layered PtSe<sub>2</sub> and PtS<sub>2</sub> were modeled by a  $1\times1$  supercell. 5L slab model was used for each type of materials, with a vacuum space of at least 20 Å in z direction. The k-mesh was sampled by a  $3\times3\times1$  k-mesh, accuracy tested by a  $5\times5\times1$  one. All atoms were relaxed until the residual force for each atom was less than 0.01 eV·Å<sup>-1</sup>.

#### Reference:

- 1. Kroemer H. A proposed class of hetero-junction injection lasers. *Proceedings of the IEEE* 1963, **51**(12): 1782-1783.
- 2. Gong X, Tong M, Xia Y, Cai W, Moon JS, Cao Y, et al. High-detectivity polymer photodetectors with spectral response from 300 nm to 1450 nm. *Science* 2009, **325**(5948): 1665-1667.
- 3. Mueller T, Xia F, Avouris P. Graphene photodetectors for high-speed optical communications. *Nat Photonics* 2010, **4**(5): 297-301.
- 4. Lee GH, Cui X, Kim P. Atomically thin p-n junctions with van der Waals heterointerfaces. *Nature* nanotechnology 2014, **9**(9): 676-681.
- 5. Britnell L, Ribeiro RM, Eckmann A, Jalil R, Belle BD, Mishchenko A, *et al.* Strong light-matter interactions in heterostructures of atomically thin films. *Science* 2013, **340**(6138): 1311-1314.
- 6. Geim AK, Grigorieva IV. Van der Waals heterostructures. Nature 2013, 499(7459): 419.
- 7. Ahmad N, Younus HA, Chughtai AH, Verpoort F. Metal-organic molecular cages: applications of biochemical implications. *Chemical Society Reviews* 2015, **44**(1): 9.
- 8. Lin S, Liu S, Yang Z, Li Y, Ng TW, Xu Z, et al. Solution Processable Ultrathin Black Phosphorus as an Effective Electron Transport Layer in Organic Photovoltaics. *Adv Funct Mater* 2016, **26**(6): 864-871.
- 9. Lin S, Chui Y, Li Y, Shu PL. Liquid-phase exfoliation of black phosphorus and its applications. *Flatchem* 2017, **2:** 15-37.
- 10. Chhowalla M, Shin HS, Eda G, Li LJ, Loh KP, Zhang H. The chemistry of two-dimensional layered transition metal dichalcogenide nanosheets. *Nature Chemistry* 2013, **5**(4): 263-275.
- 11. Xu ZQ, Zhang Y, Wang Z, Shen Y, Huang W, Xia X, et al. Atomically thin lateral p?n junction photodetector with large effective detection area. 2d Materials 2016, **3**(4).
- 12. Ghorbaniasl M, Kuc A, Miró P, Heine T. A Single-Material Logical Junction Based on 2D Crystal PdS2. *Advanced materials* 2016, **28**(5): 853.
- 13. Li P, Li L, Zeng XC. Tuning the electronic properties of monolayer and bilayer PtSe 2 via strain engineering. *J Mater Chem C* 2016, **4**(15): 3106-3112.
- 14. Deng Y, Luo Z, Conrad NJ, Liu H, Gong Y, Najmaei S, et al. Black phosphorus-monolayer MoS2 van der Waals heterojunction p-n diode. *Acs Nano* 2014, **8**(8): 8292-8299.

- 15. Furchi MM, Pospischil A, Libisch F, Burgdörfer J, Mueller T. Photovoltaic Effect in an Electrically Tunable van der Waals Heterojunction. *Nano letters* 2014, **14**(8): 4785.
- 16. Lee CH, Lee GH, Zande AMVD, Chen W, Li Y, Han M, et al. Atomically thin p–n junctions with van der Waals heterointerfaces. *Nature Nanotechnology* 2014, **9**(9): 676.
- 17. Cheng R, Li D, Zhou H, Wang C, Yin A, Jiang S, *et al.* Electroluminescence and photocurrent generation from atomically sharp WSe2/MoS2 heterojunction p-n diodes. *Nano letters* 2014, **14**(10): 5590-5597.
- 18. Pezeshki A, Shokouh SHH, Nazari T, Oh K, Im S. Electric and Photovoltaic Behavior of a Few Layer a MoTe2/MoS2 Dichalcogenide Heterojunction. *Advanced materials* 2016, **28**(16): 3216.
- 19. Roy T, Tosun M, Hettick M, Ahn GH, Hu C, Javey A. 2D-2D tunneling field-effect transistors using WSe2/SnSe2 heterostructures. *Appl Phys Lett* 2016, **108**(8): 437-435.
- 20. S J, N U, H B, AB K, AF M. Mono- and bilayer WS2 light-emitting transistors. *Nano letters* 2014, **14**(4): 2019.
- 21. Amani M, Burke RA, Proie RM, Dubey M. Flexible integrated circuits and multifunctional electronics based on single atomic layers of MoS2 and graphene. *Nanotechnology* 2015, **26**(11): 115202.
- 22. Liu N, Tian H, Schwartz G, Tok JB-H, Ren T-L, Bao Z. Large-area, transparent, and flexible infrared photodetector fabricated using PN junctions formed by N-doping chemical vapor deposition grown graphene. *Nano letters* 2014, **14**(7): 3702-3708.
- 23. Zhang Y, Ye J, Yomogida Y, Takenobu T, Iwasa Y. Formation of a stable p–n junction in a liquid-gated MoS2 ambipolar transistor. *Nano letters* 2013, **13**(7): 3023-3028.
- 24. Pospischil A, Furchi MM, Mueller T. Solar-energy conversion and light emission in an atomic monolayer pn diode. *Nature nanotechnology* 2014, **9**(4): 257-261.
- 25. Jo S, Ubrig N, Berger H, Kuzmenko AB, Morpurgo AF. Mono-and bilayer WS2 light-emitting transistors. *Nano letters* 2014, **14**(4): 2019-2025.
- 26. Geim AK, Grigorieva IV. Van der Waals heterostructures. *Nature* 2013, **499**(7459): 419-425.
- 27. Wang Y, Li L, Yao W, Song S, Sun J, Pan J, et al. Monolayer PtSe2, a New Semiconducting Transition-Metal-Dichalcogenide, Epitaxially Grown by Direct Selenization of Pt. *Nano letters* 2015, **15**(6): 4013-4018.
- 28. Wang Z, Li Q, Besenbacher F, Dong M. Facile Synthesis of Single Crystal PtSe2 Nanosheets for

- Nanoscale Electronics. Advanced materials 2016, 28(46): 10224.
- 29. Y W, L L, W Y, S S, JT S, J P, et al. Monolayer PtSe<sub>2</sub>, a New Semiconducting Transition-Metal-Dichalcogenide, Epitaxially Grown by Direct Selenization of Pt. Nano letters 2015, **15**(6): 4013.
- 30. Zhao Y, Qiao J, Yu P, Hu Z, Lin Z, Lau SP, et al. Extraordinarily strong interlayer interaction in 2D layered PtS2. Adv Mater 2016, **28**(12): 2399-2407.
- 31. Zhao Y, Qiao J, Yu Z, Yu P, Xu K, Lau SP, *et al.* High-Electron-Mobility and Air-Stable 2D Layered PtSe2 FETs. *Advanced materials* 2017.
- 32. Peng YU, Wang Q, Yu X, Liu Z. Mid-infrared 2D Photodetector based on bilayer PtSe2. Lasers and Electro-Optics; 2016; 2016. p. STu4R.5.
- 33. Li L, Wang W, Chai Y, Li H, Tian M, Zhai T. Few Layered PtS2 Phototransistor on h BN with High Gain. *Adv Funct Mater* 2017: 1701011.
- 24. Zhang K, Zhang T, Cheng G, Li T, Wang S, Wei W, *et al.* Interlayer Transition and Infrared Photodetection in Atomically Thin Type-II MoTe2/MoS2 van der Waals Heterostructures. *Acs Nano* 2016, **10**(3): 3852.
- 35. Cingolani A, Ferrara M, Lugarà M, Lévy F. The Raman Spectra of CdI2. *Solid State Commun* 1984, **50**(10): 911-913.
- 36. Roubi L, Carlone C. Resonance Raman spectrum of HfS 2 and ZrS 2. *Physical Review B* 1988, **37**(12): 6808.
- 37. O'Brien M, McEvoy N, Motta C, Zheng J-Y, Berner NC, Kotakoski J, *et al.* Raman characterization of platinum diselenide thin films. *2D Materials* 2016, **3**(2): 021004.
- 38. Chia X, Adriano A, Lazar P, Sofer Z, Luxa J, Pumera M. Layered Platinum Dichalcogenides (PtS2, PtSe2, and PtTe2) Electrocatalysis: Monotonic Dependence on the Chalcogen Size. *Adv Funct Mater* 2016, **26**(24): 4306-4318.
- 39. Zhang K, Yan M, Zhang H, Huang H, Arita M, Sun Z, *et al.* Experimental evidence of type-II Dirac fermions in PtSe2. *arXiv preprint arXiv:170304242* 2017.
- 40. Lin S, Liu Y, Hu Z, Lu W, Mak CH, Zeng L, et al. Tunable active edge sites in PtSe2 films towards hydrogen evolution reaction. *Nano Energy* 2017, **42:** 26-33.
- 41. Xu Z-Q, Zhang Y, Lin S, Zheng C, Zhong YL, Xia X, et al. Synthesis and transfer of large-area monolayer WS2 crystals: moving toward the recyclable use of sapphire substrates. ACS nano 2015, 9(6): 6178-6187.

- 42. Xue Y, Zhang Y, Liu Y, Liu H, Song J, Sophia J, *et al.* Scalable Production of a Few-Layer MoS2/WS2 Vertical Heterojunction Array and Its Application for Photodetectors. *ACS nano* 2016, **10**(1): 573-580.
- 43. Wang L, Jie J, Shao Z, Zhang Q, Zhang X, Wang Y, *et al.* MoS2/Si Heterojunction with Vertically Standing Layered Structure for Ultrafast, High-Detectivity, Self-Driven Visible-Near Infrared Photodetectors. *Adv Funct Mater* 2015, **25**(19): 2910-2919.
- 24. Zhang H, Zhang X, Liu C, Lee ST, Jie J. High-Responsivity, High-Detectivity, Ultrafast Topological Insulator Bi2Se3/Silicon Heterostructure Broadband Photodetectors. *ACS nano* 2016, **10**(5): 5113-5122.
- 45. Pezeshki A, Shokouh SH, Nazari T, Oh K, Im S. Electric and Photovoltaic Behavior of a Few-Layer alpha-MoTe2 /MoS2 Dichalcogenide Heterojunction. *Adv Mater* 2016, **28**(16): 3216-3222.
- 46. Lee CH, Lee GH, van der Zande AM, Chen W, Li Y, Han M, et al. Atomically thin p-n junctions with van der Waals heterointerfaces. *Nature nanotechnology* 2014, **9**(9): 676-681.
- 47. Furchi MM, Pospischil A, Libisch F, Burgdorfer J, Mueller T. Photovoltaic effect in an electrically tunable van der Waals heterojunction. *Nano letters* 2014, **14**(8): 4785-4791.
- 48. Kresse G, Furthmüller J. Efficient iterative schemes for ab initio total-energy calculations using a plane-wave basis set. *Physical Review B Condensed Matter* 1996, **54**(16): 11169.
- 49. Blöchl PE. Projector Agmented-Wave Method. *Physical Review B* 1994, **50**(24): 17953?17979.
- 50. Kresse G, Joubert D. From ultrasoft pseudopotentials to the projector augmented-wave method. *Physical Review B Condensed Matter* 1999, **59**(3): 1758-1775.
- 51. Klimeš J, Bowler DR, Michaelides A. Van der Waals density functionals applied to solids. *Physical Review B* 2011, **83**(19): 772-772.
- 52. Dion M, Rydberg H, Schröder E, Langreth DC, Lundqvist BI. van der Waals density functional for general geometries. *Physical review letters* 2004, **92**(24): 246401.
- 53. Lee K, Murray éD, Kong L, Lundqvist BI, Langreth DC. A Higher-Accuracy van der Waals Density Functional. *Physical Review B* 2010, **82**(8): 081101.
- 54. Hong J, Hu Z, Probert M, Li K, Lv D, Yang X, et al. Exploring atomic defects in molybdenum disulphide monolayers. *Nature communications* 2015, **6:** 6293.
- 55. Zhao Y, Qiao J, Yu Z, Yu P, Xu K, Lau SP, et al. High Electron Mobility and Air Stable 2D Layered PtSe2 FETs. Adv Mater 2017.

- 56. Qiao J, Kong X, Hu ZX, Yang F, Ji W. High-mobility transport anisotropy and linear dichroism in few-layer black phosphorus. *Nat Commun* 2014, **5:** 4475.
- 57. Wu JB, Hu ZX, Zhang X, Han WP, Lu Y, Shi W, et al. Interface Coupling in Twisted Multilayer Graphene by Resonant Raman Spectroscopy of Layer Breathing Modes. ACS nano 2015, 9(7): 7440.

### **Supporting information**

# Wafer-scale fabrication of 2D van der Waals heterojunctions for efficient and broadband photodetection

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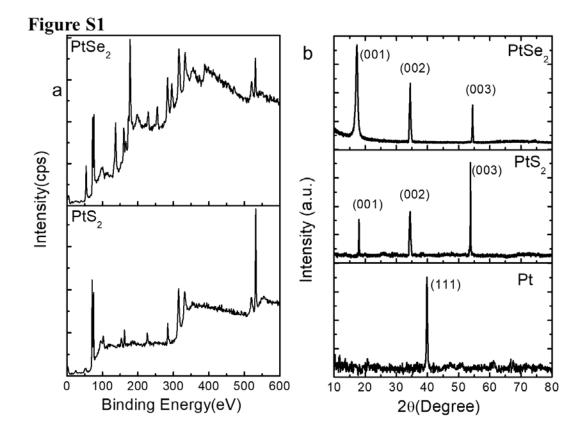


Figure S2

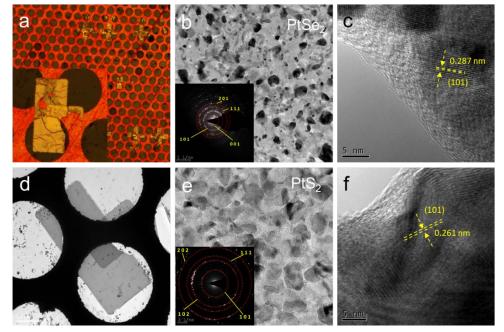


Figure S3

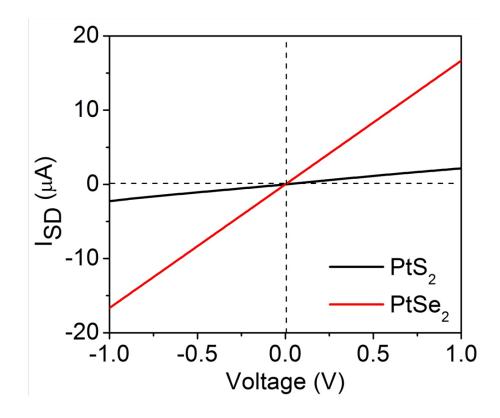


Figure S4

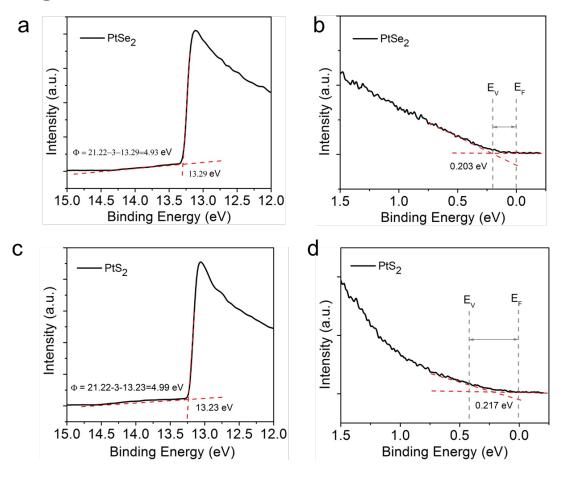
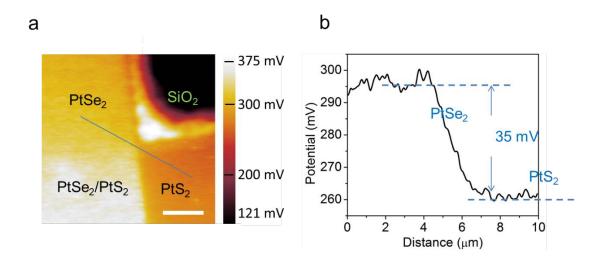


Figure S5



## Figure S6

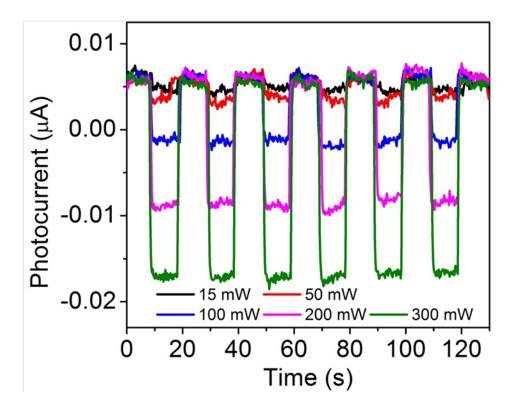
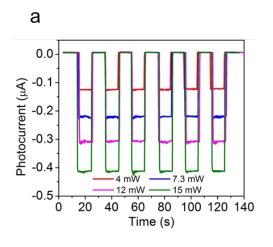


Figure S7



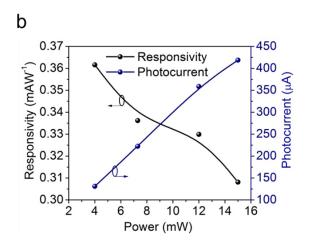


Figure S8

